

IGBT

TRENCHSTOP[™] IGBT4 Low Power Chip IGC27T120T8L

Data Sheet

Industrial Power Control



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TRENCHSTOP[™] IGBT4 Low Power Chip

Features:

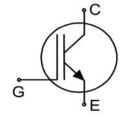
- 1200V trench & field stop technology
- Low switching losses
- Positive temperature coefficient
- Easy paralleling

Recommended for:

• Low / medium power modules

Applications:

Low / medium power drives



Chip Type	V _{CE}	<i>I</i> _{Cn} ¹	Die Size	Package
IGC27T120T8L	1200V	25A	4.99mm x 5.45mm	Sawn on foil

Mechanical Parameters

Die size		4.99 x 5.45		
Emitter pad size		See chip drawing	mm²	
Gate pad size		0.826 x 1.31	111111	
Area total		27.2		
Thickness		115	μm	
Wafer size		200	mm	
Maximum possible ch	ips per wafer	os per wafer 995		
Passivation frontside	Passivation frontside Photoimide			
Pad metal		3200nm AlSiCu		
Backside metal		Ni Ag – system To achieve a reliable solder connection it is strongly recommended not to consume the Ni layer completely during production process		
Die bond		Electrically conductive epoxy glue and soft solder		
Wire bond		Al, ≤500μm		
Reject ink dot size		Ø 0.65mm; max. 1.2mm		
Storage environment	for original and sealed MBB bags	Ambient atmosphere air, temperature 17°C – 2 < 6 months		
Storage environment	for open MBB bags	Acc. to IEC62258-3: atmosphere >99% Nitrogen or inert of humidity <25%RH, temperature 17°C – 25°C, <6 month		

 $^{^{1}}$ Nominal collector current at T_{C} =100°C for chip packaged in power modules, see application example cited on page 5.

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Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-emitter voltage, $T_{\rm vj}$ =25°C	V _{CE}	1200	V
DC collector current, limited by $T_{\rm vjmax}^{2}$	Ic	-	Α
Pulsed collector current, $t_{\rm p}$ limited by $T_{\rm vjmax}$ ³	$I_{\mathrm{C,puls}}$	75	Α
Gate-emitter voltage	V_{GE}	±20	V
Operating junction temperature	$T_{ m vj}$	-40 +175	°C
Short circuit data ^{3 / 4} V _{GE} =15V, V _{CC} =800V, T _{vj} =150°C	t _{sc}	10	μs

Static Characteristics (tested on wafer), T_{vi}=25°C

Parameter	Cumbal	Conditions	Value			Unit
Parameter	Symbol	Conditions	min.	typ.	max.	
Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{\rm GE}$ =0V, $I_{\rm C}$ =0.85mA	1200	-	-	
Collector-emitter saturation voltage	V _{CEsat}	$V_{\rm GE}$ =15V, $I_{\rm C}$ =25A	1.58	1.85	2.07	V
Gate-emitter threshold voltage	$V_{GE(th)}$	$I_{\rm C}$ =0.85mA, $V_{\rm GE}$ = $V_{\rm CE}$	5.3	5.8	6.3	
Zero gate voltage collector current	I _{CES}	$V_{\rm CE}$ =1200V, $V_{\rm GE}$ =0V	ı	ı	2.4	μA
Gate-emitter leakage current	I _{GES}	$V_{CE} = 0V, V_{GE} = 20V$		ı	120	nA
Integrated gate resistor	$r_{ m G}$			none		Ω

Electrical Characteristics ³

Parameter	Symbol	Conditions	Value			Unit
raiametei	Symbol	Conditions	min.	typ.	max.	Ullit
Collector-emitter saturation voltage	V_{CEsat}	$V_{\rm GE}$ =15V, $I_{\rm C}$ =25A, $T_{\rm vj}$ =150°C	-	2.25	-	V
Input capacitance	C _{ies}	V _{CE} =25V,	-	1450	-	nE
Reverse transfer capacitance	C _{res}	V _{GE} =0V, <i>f</i> =1MHz T _{vj} =25°C	-	50	-	pF

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 $^{^2}$ Depending on thermal properties of assembly. 3 Not subject to production test - verified by design/characterization.

⁴ Allowed number of short circuits: <1000; time between short circuits: >1s.



Further Electrical Characteristics

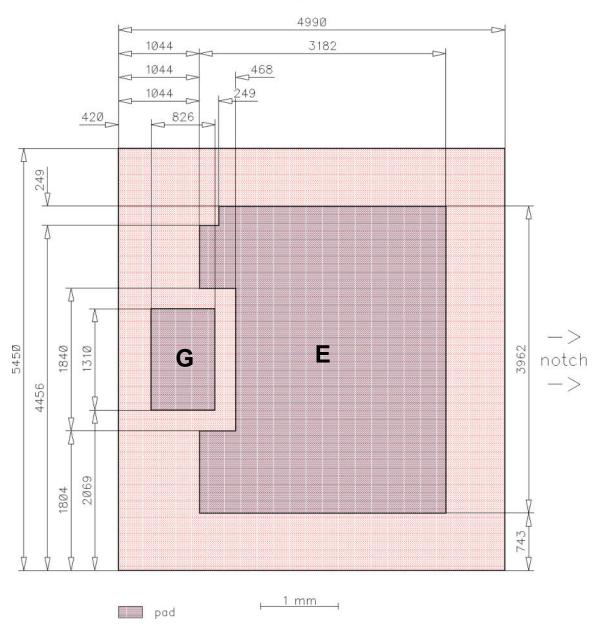
Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

Application example	FP25R12W2T4_B11	Rev. 2.1
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Chip Drawing





E = Emitter

G = Gate



Bare Die Product Specifics

Test coverage at wafer level cannot cover all application conditions. Therefore it is recommended to test all characteristics which are relevant for the application at package level, including RBSOA and SCSOA.

Description

AQL 0.65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Revision	Subjects (major changes since last revision)	Date
2.0	Final data sheet	18.02.2015
2.1	Update disclaimer	20.08.2015

Relevant Application Notes					



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